

A60 Direct Insertion Probe for Agilent 5973 & 5975

Direct Insertion Probe for the Agilent 5973 and 5973N & 5975 MSD

System Features

- Easy to install - mounts on the GC/MS Inlet Port
- PC window for the control of temperatures and ramp rates
- Ballistic ramp rate >500 degrees per minute
- Up to 25 levels of programmable temperature ramping
- Probe PC control software fully integrated with the Agilent ChemStation™ software
- Can be used with either the turbo pump or diffusion pump version of 5973 & 5975



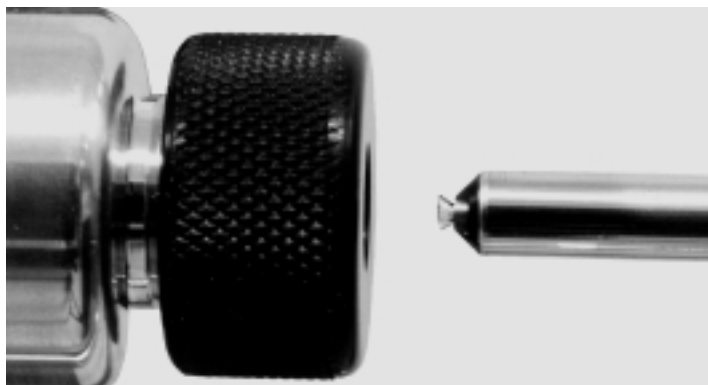
Complete Direct Probe System mounted on the Agilent 5973 MSD

Direct Probe sample analysis can be accomplished on the Agilent 5973 & 5975 MSD with the new Direct Probe Inlet System from Scientific Instrument Services™. The probe inlet mounts onto the GC/MS transfer line port and uses an indexed probe introduction guide to permit the direct insertion and removal of the probe into the MSD source without venting the MSD or scoring the probe rod. The probe can be either heated ballistically at ramp rates in excess of 500 degrees per minute or can be temperature programmed with up to 25 ramp rate levels. The probe temperatures, ramp rates, hold times, start and stop are all PC controlled and fully integrated with the Agilent ChemStation™ software. This permits the storage of the probe analysis parameters in the sample data files and the method files.

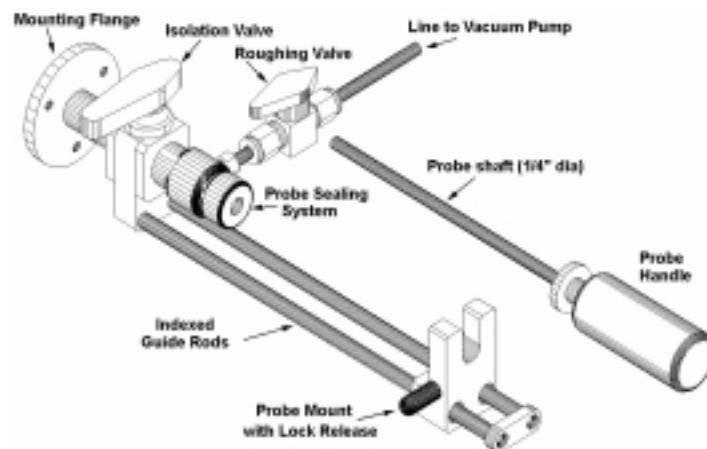
▶ **Also See:**
WEB Site for more information and accessories.
www.sisweb.com/ms/hp/5973prob.htm



Direct Probe for the Agilent 5973 & 5975



Probe Tip with sample vial ready for introduction into the MSD



Direct Insertion Probe and Probe Inlet System

The SIS™ probe for the Agilent 5973 & 5975 MSD is only 1/4" in diameter which enables it to easily slide through the probe sealing system and into the MSD. It is light in weight and comfortably fits in your hand for ease of use. The Probe tip with sample vial can be heated up to 450°C either ballistically or in the programmable mode. In the ballistic mode it will ramp up to temperature in excess of 500 degrees per minute or alternatively it can be used in the temperature ramp mode which has 25 levels of ramping capabilities to provide for the ultimate control of probe tip temperature. For cooling the probe, compressed air is used. This permits the cooling of the probe after sample analysis and before the probe is removed from the MSD through the vacuum seals. This prevents damage to the probe inlet vacuum seals.

The probe tip incorporates a small spring to gently hold the sample vial in place. The probe is designed for using glass flared sample vials. These flared sample vials permit the efficient introduction of samples (both solid and liquid) into the sample vials and permit the easy insertion and removal of the sample vials from the probe tip without breakage.